

09/84529

355	68	Subclass
ISSUE CLASSIFICATIO		

U.S. UTILITY Patent Application

M.S.	O.I.P.E.	PATENT DATE
SCANNED	QC ^{3/2} Q.A.	

APPLICATION NO. 09/845297	CONT/PRIOR F	CLASS 355	SUBCLASS 5268	ART UNIT 2851	EXAMINER A. Nattina
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Projection exposure apparatus having aberration measurement device

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ISSUING CLASSIFICATION												
ORIGINAL				CROSS REFERENCE(S)								
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
355		68		355	53	67						
INTERNATIONAL CLASSIFICATION												
G03B		27/74										
G03B		27/54										
G03B		27/42										

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	_____ (Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____	_____ (Primary Examiner) (Date)			ISSUE FEE	
				Amount Due Date Paid	
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Legal Instruments Examiner) (Date)			ISSUE BATCH NUMBER	

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